

SK75GARL07S5TD1E1



SEMITOP®E1

Symmetrical Boost

Engineering Sample SK75GARL07S5TD1E1

Target Data

Features*

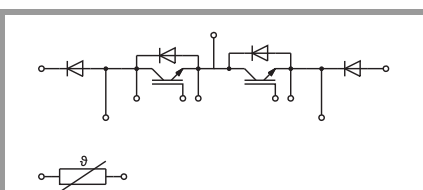
- Optimized design for superior thermal performances
- Low inductive design
- Press-Fit contact technology
- 650V Trench5 IGBT (S5)
- Rapid switching diode technology
- Integrated NTC temperature sensor
- UL recognized file no. E 63 532

Typical Applications

- UPS
- Solar

Remarks

- Recommended $T_{jop} = -40 \dots +150^{\circ}\text{C}$
- Diode1: outer Freewheeling Diodes
- Diode2: inner Antiparalell Diodes



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Absolute Maximum Ratings			
Symbol	Conditions	Values	Unit
IGBT 1			
V_{CES}	$T_j = 25^{\circ}\text{C}$	650	V
I_C	$\lambda_{paste}=0.8 \text{ W/(mK)}$	$T_s = 25^{\circ}\text{C}$	65
	$T_j = 175^{\circ}\text{C}$	$T_s = 70^{\circ}\text{C}$	51
I_C	$\lambda_{paste}=2.5 \text{ W/(mK)}$	$T_s = 25^{\circ}\text{C}$	79
	$T_j = 175^{\circ}\text{C}$	$T_s = 70^{\circ}\text{C}$	63
I_{Chom}		75	A
I_{CRM}		150	A
V_{GES}		-20 ... 20	V
t_{psc}	$V_{CC} = 360 \text{ V}$ $V_{GE} \leq 15 \text{ V}$ $V_{CES} \leq 650 \text{ V}$	$T_j = 150^{\circ}\text{C}$	not capable
T_j		-40 ... 175	$^{\circ}\text{C}$

Absolute Maximum Ratings			
Symbol	Conditions	Values	Unit
Diode 1			
V_{RRM}	$T_j = 25^{\circ}\text{C}$	650	V
I_F	$\lambda_{paste}=0.8 \text{ W/(mK)}$	$T_s = 25^{\circ}\text{C}$	63
	$T_j = 175^{\circ}\text{C}$	$T_s = 70^{\circ}\text{C}$	49
I_F	$\lambda_{paste}=2.5 \text{ W/(mK)}$	$T_s = 25^{\circ}\text{C}$	75
	$T_j = 175^{\circ}\text{C}$	$T_s = 70^{\circ}\text{C}$	59
I_{FRM}		150	A
I_{FSM}	10 ms	$T_j = 25^{\circ}\text{C}$	450
	sin 180°	$T_j = 150^{\circ}\text{C}$	380
T_j		-40 ... 175	$^{\circ}\text{C}$

Absolute Maximum Ratings			
Symbol	Conditions	Values	Unit
Diode 2			
V_{RRM}	$T_j = 25^{\circ}\text{C}$	650	V
I_F	$\lambda_{paste}=0.8 \text{ W/(mK)}$	$T_s = 25^{\circ}\text{C}$	21
	$T_j = 175^{\circ}\text{C}$	$T_s = 70^{\circ}\text{C}$	16
I_F	$\lambda_{paste}=2.5 \text{ W/(mK)}$	$T_s = 25^{\circ}\text{C}$	23
	$T_j = 175^{\circ}\text{C}$	$T_s = 70^{\circ}\text{C}$	18
I_{FRM}		30	A
I_{FSM}	10 ms	$T_j = 25^{\circ}\text{C}$	-
	sin 180°	$T_j = 150^{\circ}\text{C}$	-
T_j		-40 ... 175	$^{\circ}\text{C}$

Absolute Maximum Ratings			
Symbol	Conditions	Values	Unit
Module			
$I_{t(RMS)}$	$\Delta T_{terminal}$ at PCB joint = 30 K, per pin	30	A
T_{stg}		-40 ... 125	$^{\circ}\text{C}$
V_{isol}	AC, sinusoidal, t = 1 min	2500	V



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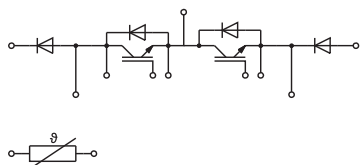
- UPS
- Solar

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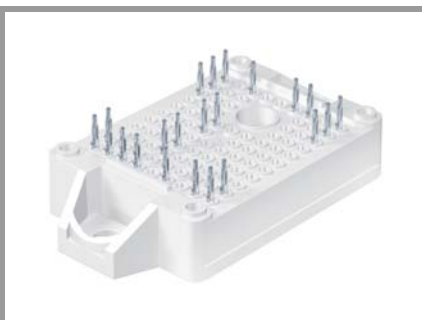
Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
IGBT 1						
$V_{CE(sat)}$	$I_C = 75\text{ A}$ $V_{GE} = 15\text{ V}$ chipllevel	$T_j = 25^\circ\text{C}$		1.42	1.75	V
		$T_j = 150^\circ\text{C}$		1.61	2.06	V
V_{CE0}	chipllevel	$T_j = 25^\circ\text{C}$		0.95	1.05	V
		$T_j = 150^\circ\text{C}$		0.85	1.00	V
r_{CE}	$V_{GE} = 15\text{ V}$ chipllevel	$T_j = 25^\circ\text{C}$		6.3	9.3	m Ω
		$T_j = 150^\circ\text{C}$		10	14	m Ω
$V_{GE(th)}$	$V_{GE} = V_{CE}, I_C = 0.75\text{ mA}$		3.2	4	4.8	V
I_{CES}	$V_{GE} = 0\text{ V}, V_{CE} = 650\text{ V}, T_j = 25^\circ\text{C}$				0.2	mA
C_{ies}	$V_{CE} = 25\text{ V}$ $V_{GE} = 0\text{ V}$	$f = 1\text{ MHz}$		4.5		nF
C_{oes}		$f = 1\text{ MHz}$		0.13		nF
C_{res}		$f = 1\text{ MHz}$		0.017		nF
Q_G	$V_{GE} = -15\text{ V} \dots +15\text{ V}$			360		nC
R_{Gint}	$T_j = 25^\circ\text{C}$			0		Ω
$t_{d(on)}$	$V_{CC} = 300\text{ V}$	$T_j = 150^\circ\text{C}$		43		ns
t_r	$I_C = 75\text{ A}$	$T_j = 150^\circ\text{C}$		34		ns
E_{on}	$V_{GE} = +15/-15\text{ V}$ $R_{Gon} = 15\ \Omega$	$T_j = 150^\circ\text{C}$		1.15		mJ
$t_{d(off)}$	$R_{Goff} = 15\ \Omega$	$T_j = 150^\circ\text{C}$		163		ns
t_f	$di/dt_{on} = 1870\text{ A}/\mu\text{s}$	$T_j = 150^\circ\text{C}$		33		ns
E_{off}	$di/dt_{off} = 1440\text{ A}/\mu\text{s}$ $dv/dt = 7220\text{ V}/\mu\text{s}$	$T_j = 150^\circ\text{C}$		1.46		mJ
$R_{th(j-s)}$	per IGBT, $\lambda_{paste}=0.8\text{ W}/(\text{mK})$			1.18		K/W
$R_{th(j-s)}$	per IGBT, $\lambda_{paste}=2.5\text{ W}/(\text{mK})$			0.87		K/W

Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
Diode 1						
V_F	$I_F = 75\text{ A}$ chipllevel	$T_j = 25^\circ\text{C}$		1.35	1.92	V
		$T_j = 150^\circ\text{C}$		1.30	1.89	V
V_{F0}	chipllevel	$T_j = 25^\circ\text{C}$		0.90	1.10	V
		$T_j = 150^\circ\text{C}$		0.71	0.94	V
r_F	chipllevel	$T_j = 25^\circ\text{C}$		6.0	11	m Ω
		$T_j = 150^\circ\text{C}$		7.9	13	m Ω
I_{RRM}	$I_F = 75\text{ A}$	$T_j = 150^\circ\text{C}$		67		A
Q_{rr}	$di/dt_{off} = 2270\text{ A}/\mu\text{s}$	$T_j = 150^\circ\text{C}$		4.36		μC
E_{rr}	$V_{GE} = -15\text{ V}$ $V_{CC} = 300\text{ V}$	$T_j = 150^\circ\text{C}$		0.98		mJ
$R_{th(j-s)}$	per Diode, $\lambda_{paste}=0.8\text{ W}/(\text{mK})$			1.39		K/W
$R_{th(j-s)}$	per Diode, $\lambda_{paste}=2.5\text{ W}/(\text{mK})$			1.06		K/W



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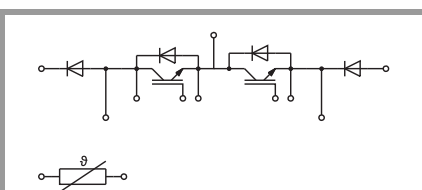
Remarks

- Recommended $T_{jop} = -40 \dots +150^\circ\text{C}$
- Diode1: outer Freewheeling Diodes
- Diode2: inner Antiparalell Diodes

Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
Diode 2						
V_F	$I_F = 15 \text{ A}$	$T_j = 25^\circ\text{C}$		1.55	1.87	V
		chipelevel	$T_j = 150^\circ\text{C}$	1.45	1.74	V
V_{F0}	chipelevel	$T_j = 25^\circ\text{C}$		1.10	1.32	V
		$T_j = 150^\circ\text{C}$		0.95	1.14	V
r_F	chipelevel	$T_j = 25^\circ\text{C}$		30	37	m Ω
		$T_j = 150^\circ\text{C}$		33	40	m Ω
I_{RRM}	$I_F = 15 \text{ A}$			-		A
Q_{rr}				-		μC
E_{rr}				-		mJ
$R_{th(j-s)}$	per Diode, $\lambda_{paste}=0.8 \text{ W/(mK)}$			3.62		K/W
$R_{th(j-s)}$	per Diode, $\lambda_{paste}=2.5 \text{ W/(mK)}$			3.27		K/W

Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
Module						
M_s	to heatsink		1.6		2.3	Nm
w	weight			25		g

Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
Temperature Sensor						
R_{25}	$T_r=25^\circ\text{C}$			22 \pm 5%		k Ω
$B_{25/50}$	$R(T)=R_{25}\exp[B_{25/50}(1/T-1/T_{25})]$; T[K]			3950 \pm 3%		K



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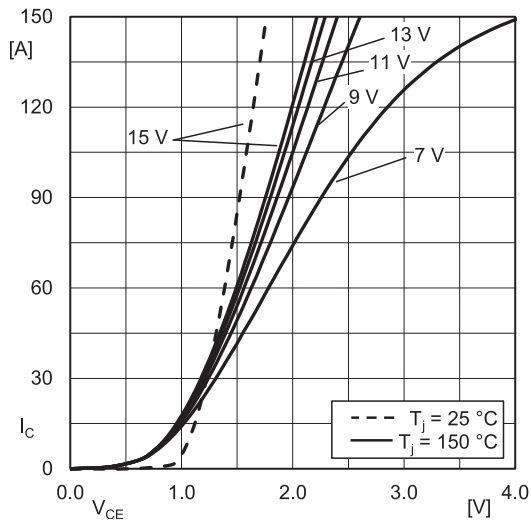


Fig. 1: Typ. IGBT output characteristic, incl. $R_{CC+EE'}$

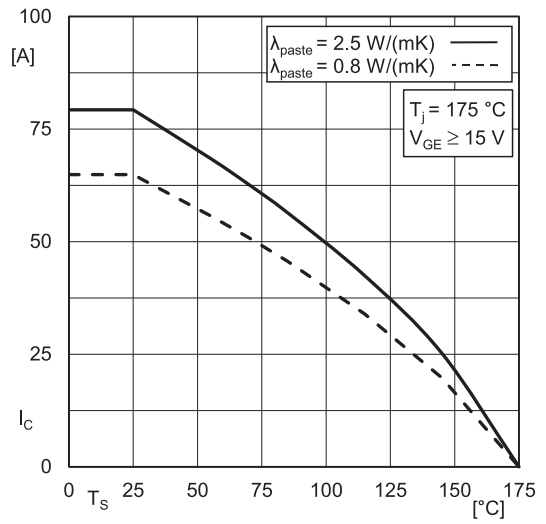


Fig. 2: IGBT rated current vs. temperature $I_c=f(T_s)$

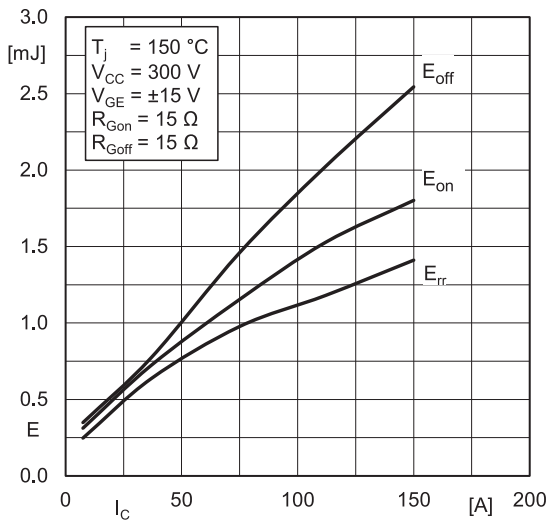


Fig. 3: Typ. turn-on /-off energy = $f(I_c)$

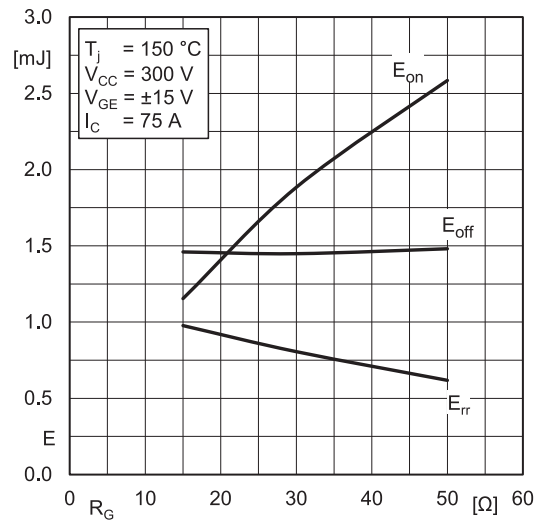


Fig. 4: Typ. turn-on /-off energy = $f(R_G)$

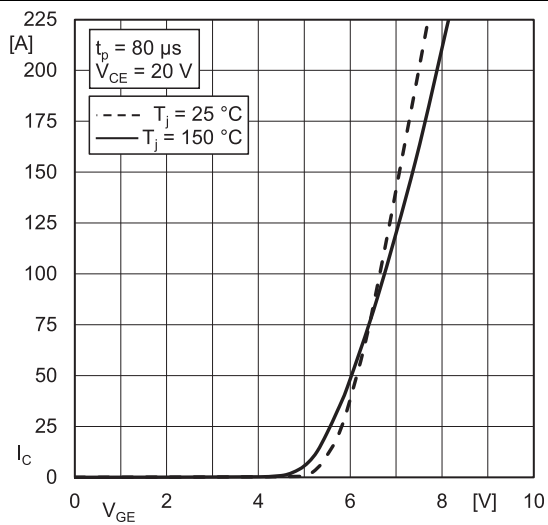


Fig. 5: Typ. IGBT transfer characteristic

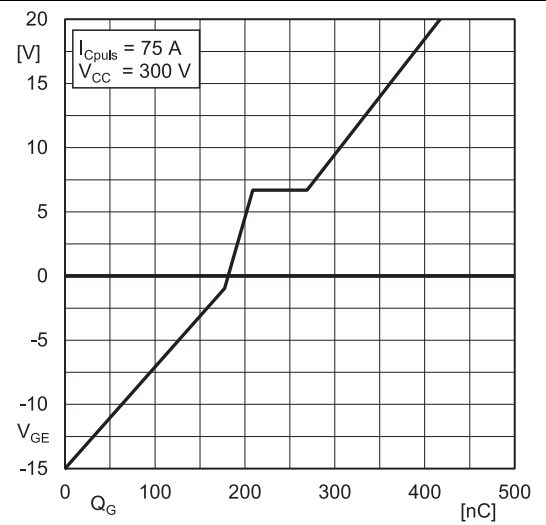


Fig. 6: Typ. IGBT gate charge characteristic

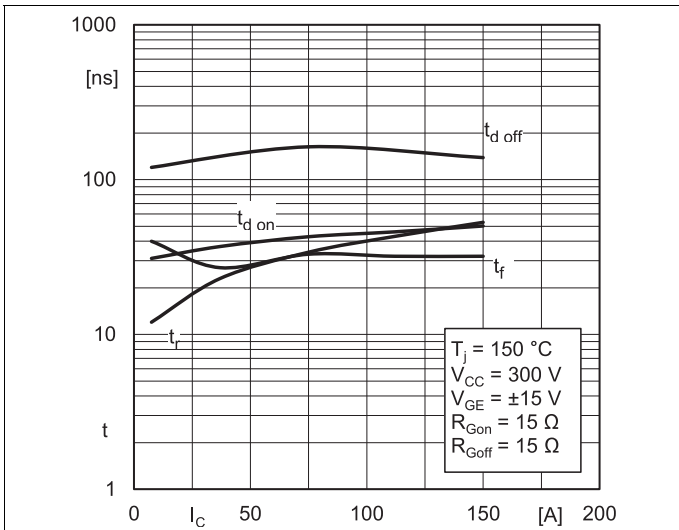


Fig. 7: Typ. switching times = $f(I_C)$

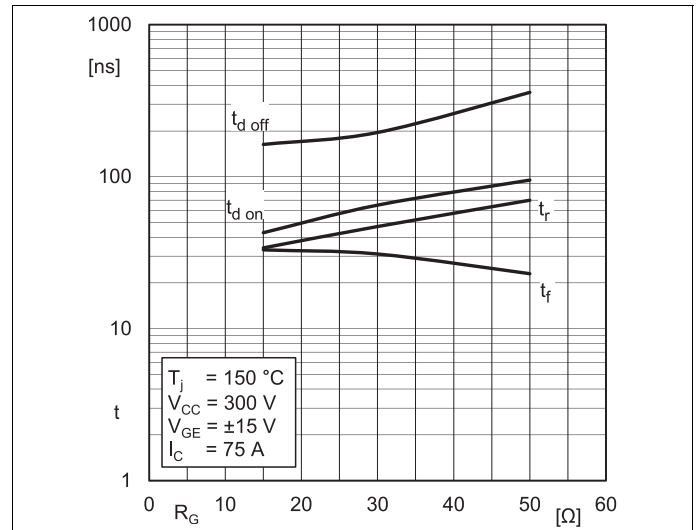


Fig. 8: Typ. switching times = $f(R_G)$

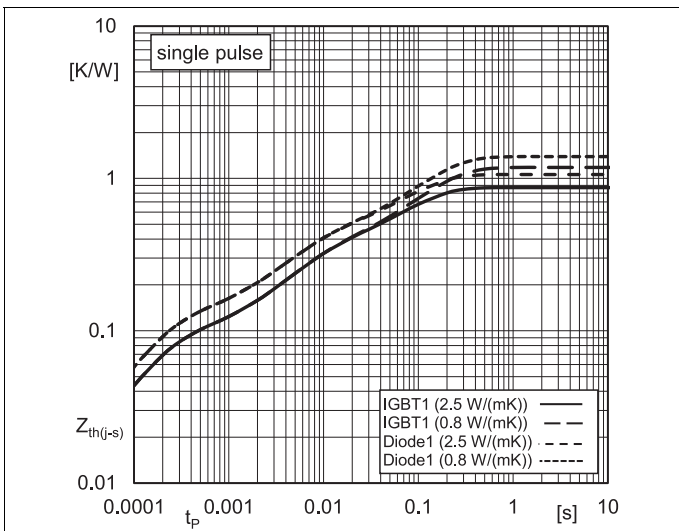


Fig. 9: Typ. transient thermal impedance

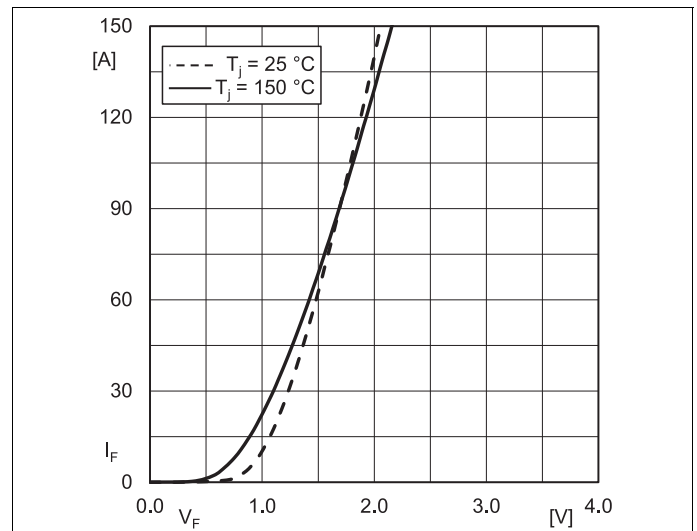


Fig. 10: Typ. Diode1 forward characteristic, incl. $R_{CC+EE'}$

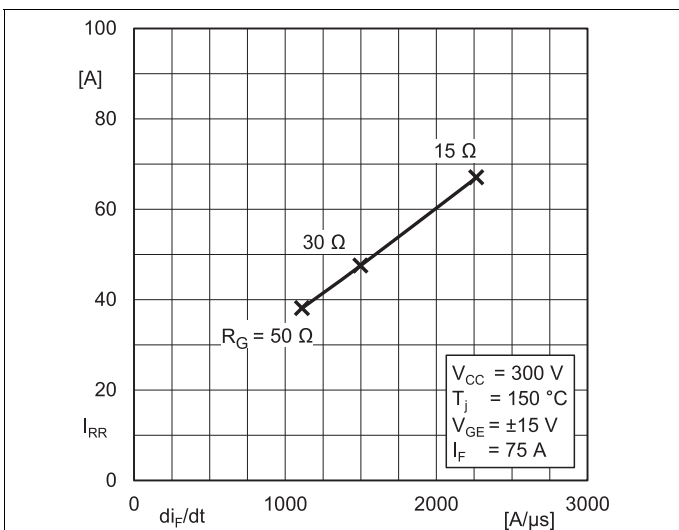


Fig. 11: Typ. Diode peak reverse recovery current

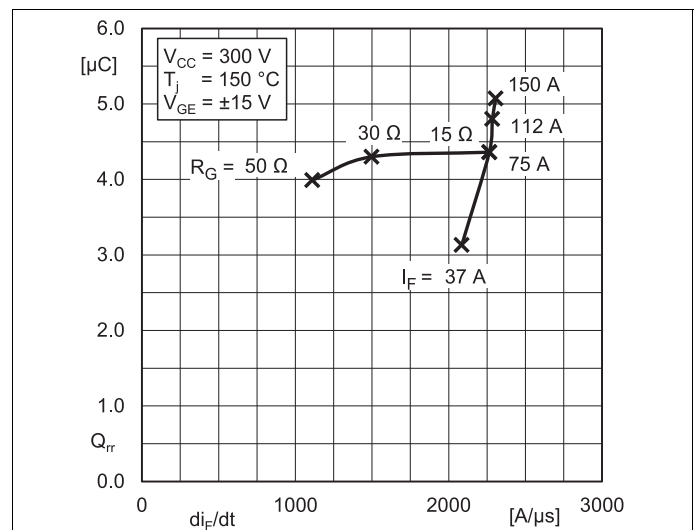
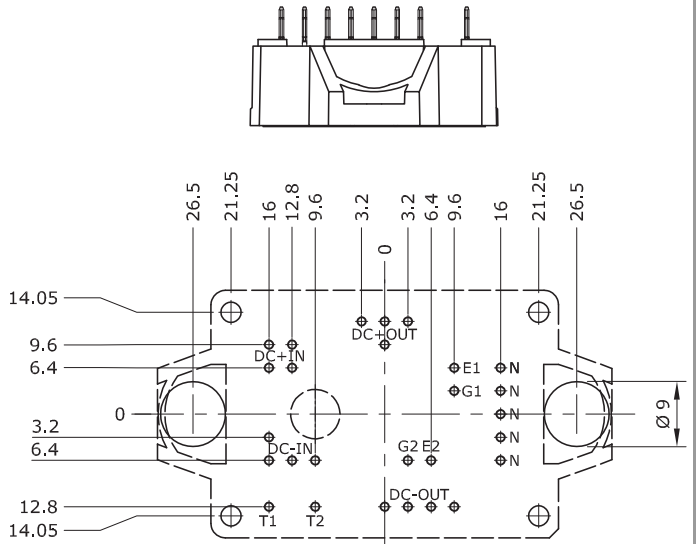
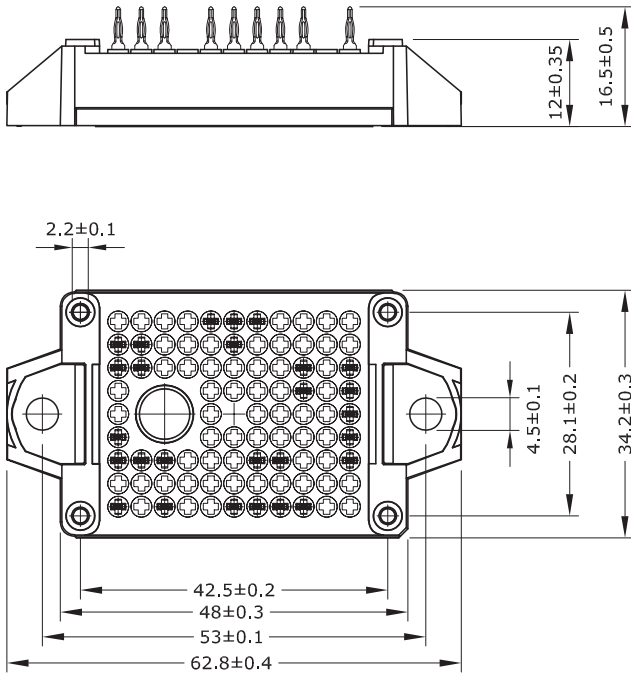


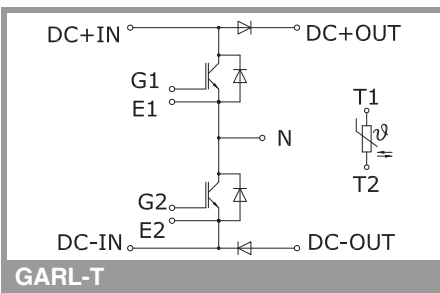
Fig. 12: Typ. Diode reverse recovery charge

SK75GARL07S5TD1E1



- Pin-Grid 3.2 mm
- Tolerance of PCB hole pattern $\pm \phi 0.1$
- Diameters of drill $\phi 1.15\text{mm}$
- Copper thickness in hole 25 - 50 μm
- Hole specification for contacts:
refer to SEMITOP E1/E2 Mounting Instruction

SEMITOP®E1



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This is an electrostatic discharge sensitive device (ESDS) due to international standard IEC 61340.

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